

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/038,136 CLEWIS ET AL.	
		Examiner	Art Unit Satish S. Rampuria	2124 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0162096 A1	10-2002	Robison, Arch D.	717/145
	B	US-6,064,819 A	05-2000	Franssen et al.	717/156
	C	US-5,887,174 A	03-1999	Simons et al.	717/161
	D	US-5,867,711 A	02-1999	Subramanian et al.	717/161
	E	US-5,838,977 A	11-1998	Gupta, Anil	717/156
	F	US-5,671,419 A	09-1997	Carini et al.	717/145
	G	US-5,606,698 A	02-1997	Powell, Douglas B.	717/161
	H	US-6,681,221 B1	01-2004	Jacobs, Ronald Michael	707/5
	I	US-6,292,938 B1	09-2001	Sarkar et al.	717/138
	J	US-6,654,761 B2	11-2003	Tenev et al.	707/102
	K	US-6,055,539 A	04-2000	Singh et al.	707/102
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fetterer et al., A performance analysis of hierarchical shortest path algorithms, Tools with Artificial Intelligence, 1997. Proceedings., Ninth IEEE International Conference on , 3-8 Nov. 1997, Pages: 84 - 93
	V	Dell et al., An object oriented data model for Web and its algebra, Technology of Object-Oriented Languages and Systems, 1999. TOOLS 31. Proceedings , 22-25 Sept. 1999, Pages:83 - 88
	W	Chew et al., An object-oriented OSI event and log manager, Networks, 1995. Theme: 'Electrotechnology 2000: Communications and Networks'. International Conference on Information Engineering., Proceedings of IEEE, July 1995, Pages:256 - 260
	X	Kramer et al., The combining DAG: a technique for parallel data flow analysis, Parallel and Distributed Systems, IEEE Transactions on , Volume: 5 , Issue: 8 , Aug. 1994, Pages:805 - 813

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.